## nexperia

## **Quarterly Reliability Monitoring Results**

Quarters: Q3/2021 to Q4/2022

Based on structural similarity

Supplier		User Part Number					
Nexperia B.V.		PTVS58VS1UR					
Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		Part Description					
		Nexperia DHAM	Protection				
		SMD package					
		Test Conditions	Duration	# Lots	# Quantity	# Rejects	
	TEST						
	Pre- and Post-Stress						
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below	
		JESD22-A113					
		Bake Tamb = 125 °C	24 hours				
	PC	Soak Tamb = 85 °C, RH = 85%	168 hours				
# A1	Preconditioning	Reflow soldering	3 cycles	438	24630	0	
		MIL-STD-750-1					
	HTRB	M1038 Method A					
	High Temperature Reverse Bias	Tj = Tjmax, Vr = 100% of max. datasheet reverse voltage	10001		10010	•	
# B1	DIdS	reverse voltage	1000 hours	166	10040	0	
	тс	JESD22-A104					
# 14	Temperature Cycling	-65 °C to Tjmax, not to exceed 150°C	1000 cycles	131	7760	0	
# A4	Temperature cycling		1000 Cycles	151	7760	0	
	UHAST	JESD22-A118					
# A3 <b>or</b>	Unbiased HAST	Tamb = 130 °C, RH = 85 %					
		JESD22-A102	— 96 hours	131	7760	0	
	AC	Tamb = $121 ^{\circ}C$ , RH = $100 ^{\circ}M$					
# A3 alt	Autoclave	Pressure = $205 \text{ kPa} (29.7 \text{ psia})$					
	H3TRB	JESD22-A101					
	High Humidity High	Tamb = 85 °C, RH = 85%, VR = 80 % of					
# A2 alt	Temperature Reverse Bias	rated reverse voltage <sup>[1]</sup>	1000 hours	131	7760	0	
		MIL-STD-750 Method 1037					
	IOL	ton = toff, devices powered to insure $\Delta Tj$ =					
# A5	Intermittent Operating Life	100 °C for 15000 cycles	1000 hours	n.a.	n.a.	n.a.	
	RSH	JESD22-A111					
# C8		260 °C ± 5 °C	10 s	45	1350	0	
	SD Caldarahilitu	1 575 003					
# C10	Solderability	J-STD-002		111	1110	0	

[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia DHAM	Protection	10040	0	0,42	2,36E+09

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